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Peter Lorenz and Walter Jung*

Institut für Anorganische Chemie, Universität zu Köln, Greinstrasse 6, D-50939 Köln, Germany

Correspondence e-mail: walter.jung@uni-koeln.de

Key indicators

Single-crystal X-ray study T = 294 K Mean σ (Si–Si) = 0.003 Å R factor = 0.018 wR factor = 0.044 Data-to-parameter ratio = 13.7

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MgIr₃Si₇, a new magnesium iridium silicide with the ScRh₃Si₇ type structure

The title compound, magnesium triiridium heptasilicide, was synthesized by reaction of the elemental components in a sealed tantalum container. It crystallizes in space group $R\overline{3}c$ and adopts the ScRh₃Si₇ structure type. Mg, Ir and one of the two cystallographically independent Si atoms are in special positions with site symmetries $\overline{3}$, 2 and 32, respectively. MgIr₃Si₇ shows metallic conductivity and remarkable chemical inertness.

Comment

In the course of our studies of alkaline earth transition metal silicides, we were able to synthesize five ternary phases in the system Mg–Ir–Si: $Mg_{15}Ir_5Si_2$ (Lorenz *et al.*, 2002) and Mg_3Ir_3Si_8 (Jung, 2006) crystallize with their own structures, Mg_2IrSi (Schoolaert, 1995) is isotypic with Mg_2PtSi (Range *et al.*, 1990), and MgIrSi adopts the TiNiSi structure type (Shoemaker & Shoemaker, 1965). Here, we report on MgIr_3Si_7, which is isotypic with ScRh_3Si_7 and ScIr_3Si_7 (Chabot *et al.*, 1981).

The ScRh₃Si₇ structure type has been described by Chabot *et al.* (1981). Following this description, the structure of the isotypic compound MgIr₃Si₇ may be interpreted on the basis of a hexagonal close-packed arrangement of the Ir atoms, with six layers per unit cell stacked along the *c* axis. However, the Ir···Ir distances, in the range 4.1248 (5)–4.4070 (6) Å, are far above the bonding distance. The Mg atoms occupy one third of the octahedral interstices in an ordered manner. Fig. 1 shows two layers of Ir atoms (*A* and *B*) forming a sheet of edge-connected octahedra. If the three possible positions for an octahedrally coordinated Mg atom in the *ab* plane are



Figure 1

The sheet of edge-connected octahedra formed by the stacking of two layers of Ir atoms A and B, in a projection along [0001]. The unit cell is outlined. Possible positions of the Mg atoms are denoted by $\gamma 1$, $\gamma 2$ and $\gamma 3$.

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Figure 2

A section of the structure, showing the formation of Si_7 double tetrahedra by Si atoms centring one out of two triangular faces of every empty Ir octahedron. Mg atoms are red, Ir blue and Si black.



Figure 3

The arrangement of Si₇ double tetrahedra and MgIr₆ octahedra in a slab around the $(11\overline{2}0)$ plane. Colour code as in Fig. 2.

denoted by $\gamma 1$, $\gamma 2$ and $\gamma 3$, then the stacking sequence for Ir atoms (A, B) and Mg atoms (γ) can be expressed by $A\gamma 1B\gamma 2 A\gamma 3B\gamma 1 A\gamma 2B\gamma 3$.

As illustrated in Fig. 2, the Si atoms centre four of the eight triangular faces of every empty Ir_6 octahedron in such a way that Si₇ double tetrahedra are formed. Fig. 3 shows the arrangement of the MgIr₆ octahedra and the Si₇ double tetrahedra in a slab around the plane (1120). The Si···Si distances in the double tetrahedra are 2.577 (3) (Si1···Si1^{vi}) and 2.6980 (17) Å (Si1···Si2^{vii}) (symmetry codes as in Table 1), much larger than the distance of 2.351 Å in elemental silicon (Toebbens *et al.*, 2001). Thus, only weak Si–Si bonding can be expected.



Figure 4

The environment of the Ir atoms, drawn with anisotropic displacement parameters at the 99% probability level. Colour code as in Fig. 2.





The shortest distances in the structure are those between the Si and Ir atoms. These are in the range 2.418 (2)– 2.505 (2) Å and are thus close to the sum of the covalent radii, but considerably shorter than the sum of the metallic radii for coordination number (CN) 12 (2.438 and 2.730 Å, respectively; Pauling, 1973). Short distances between transition metals and Si atoms are frequently observed in binary and ternary silicides. In IrSi, for example, the Ir–Si distances range between 2.316 and 2.563 Å (Göransson *et al.*, 1995).

The environment of the Ir atoms, shown in Fig. 4, consists of seven Si and two Mg atoms and it is quite irregular. The Mg···Ir distance [3.040 (1) Å] and the Mg···Si distances [3.117 (2) and 3.144 (2) Å] are larger than the corresponding sums of the metallic radii for CN 12 (2.953 Å for Mg–Ir and 2.973 Å for Mg–Si; Pauling, 1973). This is possibly due to the large CN of 18 for the Mg atoms. The cage for the Mg atoms shown in Fig. 5 is formed by six Mg and 12 Si atoms.

Experimental

Single crystals of $MgIr_3Si_7$ were obtained from a mixture of the elemental components (Mg 99.8%, raspings prepared from a rod,

Ventron; Ir 99.9%, powder, Degussa; Si m4N, powder, Ventron) of composition MgIrSi₂ annealed at 1473 K for 3 d in a sealed tantalum tube under an argon atmosphere and cooled to room temperature at a rate of 5 K h⁻¹. For the synthesis of single phase MgIr₃Si₇, a prealloy of composition Ir₃Si₇ was first prepared by arc melting under an argon atmosphere. The button obtained was crushed and powdered in a boron carbide mortar and mixed with the appropriate amount of magnesium raspings. The sample was annealed in a sealed tantalum tube under an argon atmosphere for 1 d and cooled to room temperature at a rate of 100 K h⁻¹. The product thus obtained was a grey sintered powder of remarkable chemical inertness. Even upon treatment with aqua regia, no attack was observed.

The temperature dependence of the resistivity of a sintered powder specimen was measured using a four-point DC device. The resistivity decreased nearly linearly from $4.3 \text{ m}\Omega$ cm at 300 K to $3.2 \text{ m}\Omega$ cm at 4.2 K. This is indicative of a poor metal.

Crystal data

 $\begin{array}{l} {\rm MgIr_{3}Si_{7}} \\ M_{r} = 797.54 \\ {\rm Trigonal}, \ R\overline{3}c \\ a = 7.5232 \ (8) \ {\rm \AA} \\ c = 19.959 \ (3) \ {\rm \AA} \\ V = 978.3 \ (2) \ {\rm \AA}^{3} \\ Z = 6 \end{array}$

Data collection

Stoe IPDS-I diffractometer ω scans Absorption correction: numerical [X-RED (Stoe & Cie, 2001), after optimizing the crystal shape using X-SHAPE (Stoe & Cie, 1999)] $T_{\min} = 0.096, T_{\max} = 0.306$

Refinement

Refinement on F^2 $R[F^2 > 2\sigma(F^2)] = 0.018$ $wR(F^2) = 0.044$ S = 1.06 274 reflections 20 parameters $w = 1/[\sigma^2(F_o^2) + (0.0238P)^2 + 9.1966P]$ where $P = (F_o^2 + 2F_c^2)/3$ 2857 measured reflections 274 independent reflections 241 reflections with $I > 2\sigma(I)$ $R_{int} = 0.048$ $\theta_{max} = 28.1^{\circ}$

 $D_x = 8.122 \text{ Mg m}^{-3}$

Parallelepiped, black

0.06 \times 0.04 \times 0.03 mm

Mo $K\alpha$ radiation $\mu = 62.33 \text{ mm}^{-1}$

T = 294 (3) K

 $\begin{array}{l} (\Delta/\sigma)_{\rm max} < 0.001 \\ \Delta\rho_{\rm max} = 1.28 \ {\rm e} \ {\rm \AA}^{-3} \\ \Delta\rho_{\rm min} = -1.28 \ {\rm e} \ {\rm \AA}^{-3} \\ {\rm Extinction \ correction: \ SHELXL97} \\ ({\rm Sheldrick, \ 1997}) \\ {\rm Extinction \ coefficient: \ 0.00157 \ (7)} \end{array}$

Table 1

Selected bond lengths (Å).

Ir–Si1 ⁱ	2.4183 (18)	Mg-Si1 ^v	3.1168 (17)
Ir-Si2	2.4359 (4)	Mg-Si1 ^{vi}	3.1438 (18)
Ir-Si1 ⁱⁱ	2.4449 (17)	Si1-Si1 ^{vi}	2.577 (3)
Ir-Si1 ⁱⁱⁱ	2.5048 (17)	Si1-Si2 ^{vii}	2.6980 (17)
Ir–Mg ^{iv}	3.0398 (3)	Si2-Ir ^{viii}	2.4359 (4)

Symmetry codes: (i) $x - y + \frac{2}{3}, x - \frac{2}{3}, -z + \frac{1}{3}$; (ii) $x - y + \frac{1}{3}, -y + \frac{2}{3}, -z + \frac{1}{6}$; (iii) $-x + y + \frac{1}{3}, y - \frac{1}{3}, z + \frac{1}{6}$; (iv) $x + \frac{2}{3}, y + \frac{1}{3}, z + \frac{1}{3}$; (v) $-y + \frac{2}{3}, -x + \frac{1}{3}, z - \frac{1}{6}$; (vi) -x + y, -x + 1, z; (vii) $x + \frac{1}{3}, y + \frac{2}{3}, z - \frac{1}{3}$; (viii) -x + y, -x, z.

Lattice parameters were obtained from a Guinier pattern completely indexed on the basis of the single-crystal data [Cu $K\alpha_1$, $\lambda = 1.5406$ Å, Si as internal standard, least-squares refinement (Bach, 1978)]. The highest peak is located 1.27 Å from Si1 and the deepest hole 0.76 Å from Ir.

Data collection: X-AREA (Stoe & Cie, 2001); cell refinement: Guinier film method (Bach, 1978); data reduction: X-AREA (Stoe & Cie, 2001); program(s) used to solve structure: SHELXS97 (Sheldrick, 1997); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); molecular graphics: DIAMOND (Brandenburg, 1999); software used to prepare material for publication: SHELXL97.

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